Contents

Vols. 114 and 115, 1994

Preface 1

Invited Speakers

Correction Procedures in Electron Probe Microanalysis of Bulk Samples
P. Duncumb 3

Recent Progress in Quantitative and High Spatial Resolution AES
S. Hofmann 21

Standardless X-Ray Analysis of Bulk Specimens
J.-L. Pouchou 33

Standardless Quantitation of Thin Film Specimens
W.-A. P. Nicholson 53

Electron Energy Loss Spectrometry Mapping
Ch. Colliex, M. Tencé, E. Lefèvre, C. Mory, H. Gu, D. Bouchet, Ch. Jeanguillaume 71

Quantitative Analysis of Films by Ion Microbeam Methods. I: RBS, NRA, and Channeling
A. V. Drigo 89

Quantitative Analysis of Films by Ion Microbeam Methods. II: SIMS
H. Werner 107

Quantitative Microbeam Analysis of Particles
P. Van Espen 129

Environmental Scanning Electron Microscopy and Microanalysis
G. D. Danilatos 143

Contributed Papers

Composition of Vanadium Carbides Formed by Solidification in Ternary Fe-V-C Alloys
S. E. Amara, R. Kesri, N. Valignat , S. Hamar-Thibault 157

Investigation of Implanted Gallium Depth Distributions in ZnS_xSe_{1-x} by EPMA
N. Ammann, G. Gleitsmann, M. Heuken, K. Heime, P. Karduck 165

Electron and Ion Beam Analysis of Composition and Strain in Si_{1-x} Ge_x/Si Heterostructures
A. Armigliato, D. Govoni, R. Balboni, St. Frabboni, M. Berti, F. Romanato, A. V. Drigo 175

X-Ray Emission Modulation by Electron Channelling and Site Occupancy in Garnets
R. Balboni, St. Frabboni, R. Rinaldi, S. Spigarelli 187

Quantitative EPMA of Element Depth Distribution
A. Berner, G. Proaktor 195

Influence of Channeling Effects on Ion Distribution and Damage Profiles During High Energy Ion Implantation in Si
A. Carnera, A. Gasparotto, M. Berti, R. Fabbri 205

Surface and Interface Analysis of Titanium Nitride Diffusion Barriers
M. Bonelli, A. Miotello, L. Calliari, F. Romanato, A. V. Drigo, A. Carnera . . . 213

Determining the Local Coordination of Aluminium in Cement Using Electron Energy Loss Near-Edge Structure
R. Brydson, I. G. Richardson, G. W. Groves 221

Elaboration and Characterisation of Yttria PSZ Coatings Deposited by RF Sputtering on Silicon
P. Chainiau, E. Beauprez, M.-Ch. Sainte Catherine 231

Changes in Depth Profiles of Oxygen and Copper in Y-Ba-Cu-O Film under Annealing
L. P. Chernenko, A. P. Kobzev, D. A. Korneev, D. M. Shirokov 239

Damage in Y-Ba-Cu-O Films Produced by ^{4}He Ions
L. P. Chernenko, A. P. Kobzev, D. A. Korneev, D. M. Shirokov 247

An EELS and EXELFS Study of Amorphous Hydrogenated Silicon Carbide
A. Cook, A. G. Fitzgerald, F. Ibrahim, J. I. B. Wilson, Ph. John 255

Theoretical Simulation of Backscattered Electron Images of Si/Si_xGe_{1-x} Structures with a Scanning Electron Microscope
A. C. De Riccardis, P. G. Merli, M. Nacucchi, L. Tapfer 261

Analysis of Light Elements in Superposed Layers by Monte Carlo Simulation of EELS Spectra
A. Desalvo, R. Rosa, A. Armigliato, A. Parisini 267

Quantitative EPMA and TEM of Unsupported Films
J. M. Dijkstra, G. F. Bastin, H. J. M. Heijligers, D. Klepper 277

Silicate Particles Engulfed in Human Alveolar Macrophages: An Analytical Electron Microscopy Study
M. Dociaiuti, M. Falchi, L. Paoletti 285

Quantification of the Electron Beam Damage of Thin Films
L. Frank 293

Monte Carlo Correction Programme for PC
O. Gedeon, V. Hulinsky 305

Performance of a Nuclear Microprobe to Study Giant Marine Aerosol Particles
J. Injuk, L. Breitenbach, R. Van Grieken, U. Wätjen 313

The Role of Coating Densities in X-Ray Microanalysis
K. Jurek, O. Renner, E. Krouský 323

Analytical, Structural and Electrical Characterization of SiGe Layers by Electron Microbeam Techniques
M. Kittler, J. Lärz 327

Homogeneity Studies of Powders and Plasma Sprayed Deposits
B. Kolman, J. Forman, J. Dubský, P. Chráska 335

X-Ray Emission Spectroscopy with EPMA Applied to High T_c Superconductors Using New Spectrometer Crystals
A. Kottmann, P. Lamparter, S. Steeb 343

Microprecipitation in Boron-Containing High-Carbon Steels
L. Lanier, G. Metauer, M. Moukassi 353

An Accurate Computer Correction Program for Quantitative Electron Probe Microanalysis
C. Merlet 363

Investigation of Various SiC Materials by Means of EPMA/WDS Techniques
P. Moretto, P. Hoffmann 377

Use of Cathode Lens in Scanning Electron Microscope for Low Voltage Applications
I. Müllerová, L. Frank 389

Physico-Chemical Characterization of Crystalline Phases in Fly Ashes
L. Paoletti, M. Diociaiuti, A. Gianfagna, G. Viviano 397

Electron Probe Microanalysis of Dried Biological Substances
A. Pogorelov, V. Pogorelova, S. Smirnova, N. Spiridonov 405

Spatial Resolution Limitation in Auger Microanalysis of Compounds
B. A. Polonsky, O. D. Protopopov 413

X-Ray Microanalysis of Thin Film Layered Specimens Containing Light Elements
D. G. Rickerby, J.-F. Thiot 421

Structural Characterization Techniques for the Analysis of Semiconductor Strained Heterostructures
F. Romanato, M. Berti, M. Mazzer, A. V. Drigo, L. Lazzarini, P. Franzosi, G. Salviati, D. Bertone 431

PIXE and EMP Analyses of Volcanites from Nea Kameni Island (Aegean Sea, Greece)
A. P. Santo, J. D. Mac Arthur, P. Manetti 441

Application of Analytical Transmission Electron Microscopy to the Characterization of Interlayers in Fibre-reinforced Composites with Ceramic and Glass Matrices
R. Schneider, J. Woltersdorf, E. Pippel, A. Hähnel, A. Röder 453

Signal-to-Background in EPMA: Measurement and Monte Carlo Calculation
V. Stary 463

EPMA Analysis of Float Glass Surfaces
A. Stella, M. Verità 475

SIMS and Auger Investigation of Oxygen Adsorption on Polycrystalline Nickel Surface
Z. Tass, K. V. Josepovits 481

New Developments in Theory of Fast Electron Scattering in Solids: Applications to Microbeam Analysis
I. S. Tilinin, W. S. M. Werner 485

SIMS Imaging: Apparatus and Applications
A. B. Tolstogouzov, T. I. Kitaeva, S. S. Volkov 505

Combined EPMA and AES Depth Profiling of a Multilayer Ti-Al-O-N Coating
A. von Richthofen, M. Matsuo, P. Karduck, N. Ammann 511

Quantitative Analysis of W-C:H Coatings by EPMA, RBS (ERD) and SIMS
P. Willich, M. Wang, K. Wittmaack 525

Study of Chemical Bonds in a—B/C:H Films by Electron Probe Microanalysis
R. K. Zalavutdinov, A. E. Gorodetsky, A. P. Zakharov 533

X-Ray Mapping of Freeze-Dried Cryosections from Biological Cells
K. Zierold, S. V. Buravkov 539

News Section

Conference Calendar 545

Impressum 548

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